



Welcome to
046188 Winter semester 2012
Mixed Signal Electronic Circuits
Instructor: Dr. M. Moyal

Lecture 7 (part a)

FLASH ADC ARCHITECTURE ALTERNATIVES

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ALTERNATIVE DESIGNS OF FLASH ADC

SUB-RANGING ADC

Charge Flash architecture

Differential Architecture



FLASH ADC- SUMMARY

Bad-Good

Monotonic

Very fast, No amplifiers, Resistors can match well to 10b

Design Issues:

Big input capacitance

Comparator offset is an issue

Clocking routing sampling time

Meta stability

Decoding to avoid bubbles

If S/H is used – Distortion added

Hardware:

Exponential in complexity

High in power for 7 bits or more (127 comparators)

Could lead to large die size

References may need to be filtered from kick back

Medium: to scale down in technology → power supply!

Power ~ 2 to N

Area ~ 2 to N

Cin ~ 2 to N

R ladder ~ 2 to N

Here N is an increase of effective resolution

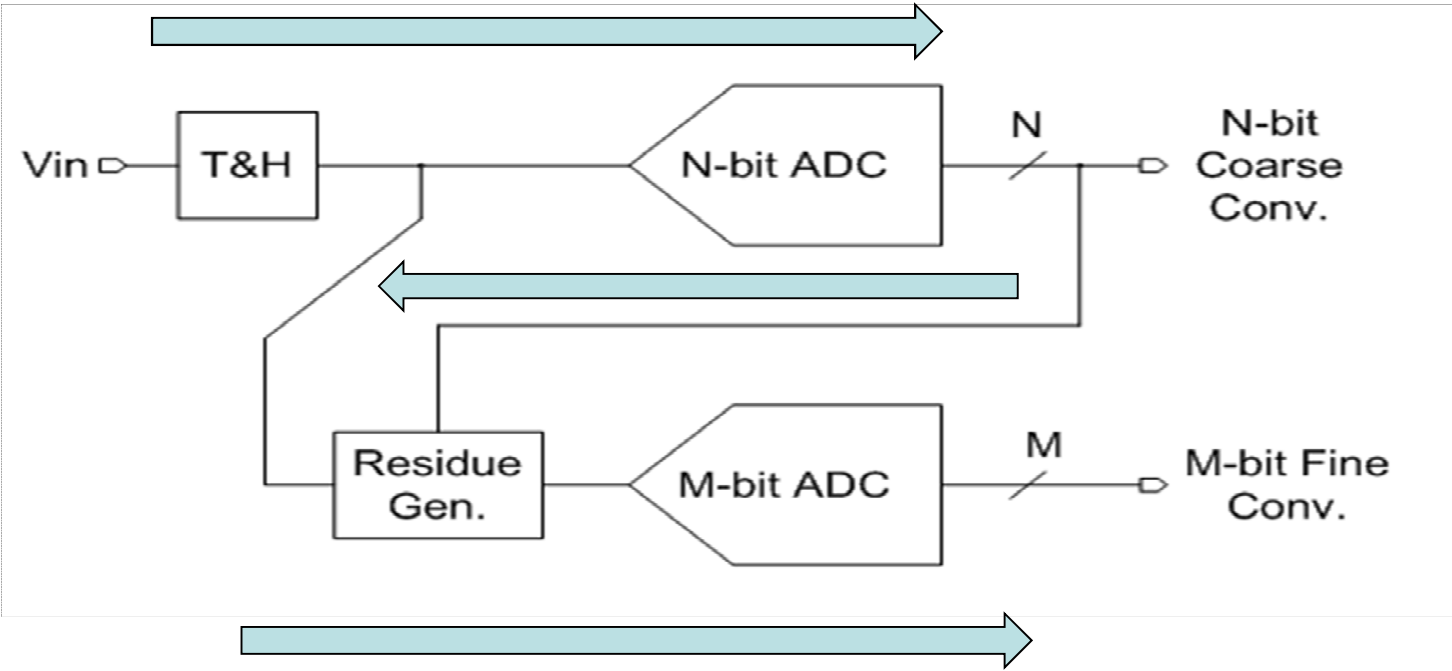


Since Flash ADC in silicon Area and Power grows exponentially . How about different architecture

Sub-ranging ADCs

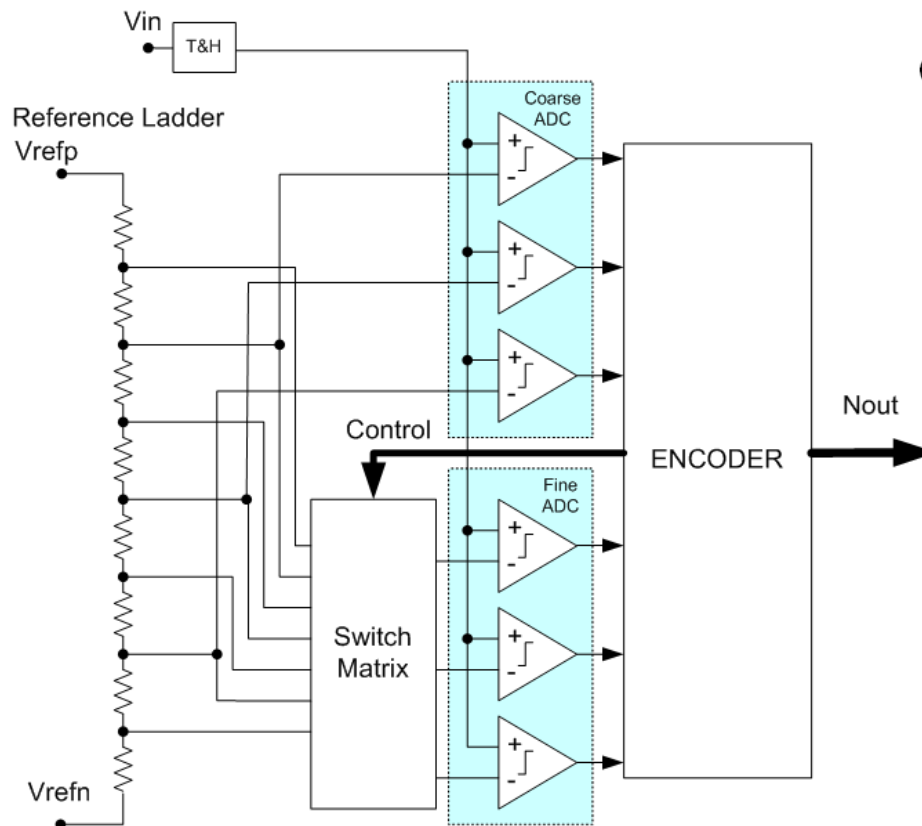


Concept





Sub-Ranging ADC Basics



Conversion is done in two steps

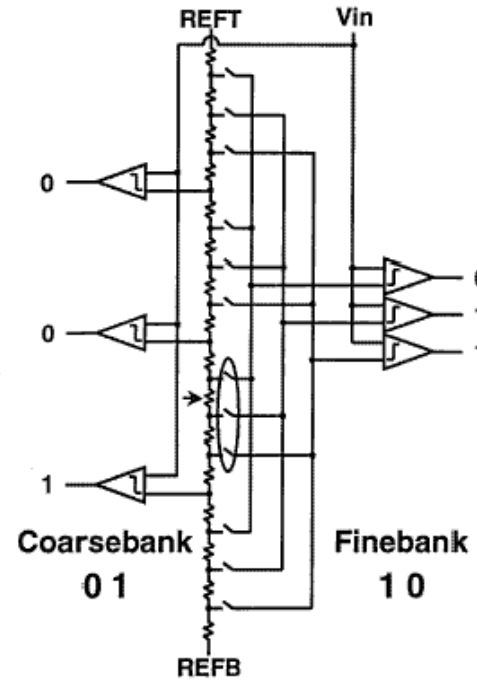
- coarse ADC determines the region of the ladder the fine ADC will use
- regions can overlap to produce the redundancy that relaxes the offset requirement for the coarse ADC
- for the fine ADC – strict offset requirements

Fine is waiting for the Coarse (MSBs) – need S/H
How to partition ? 10 bit can use 31 comparators for Coarse and 32 for fine = 63 instead of 1024
Or 63 for coarse (6 bit) and 15 for fine ?



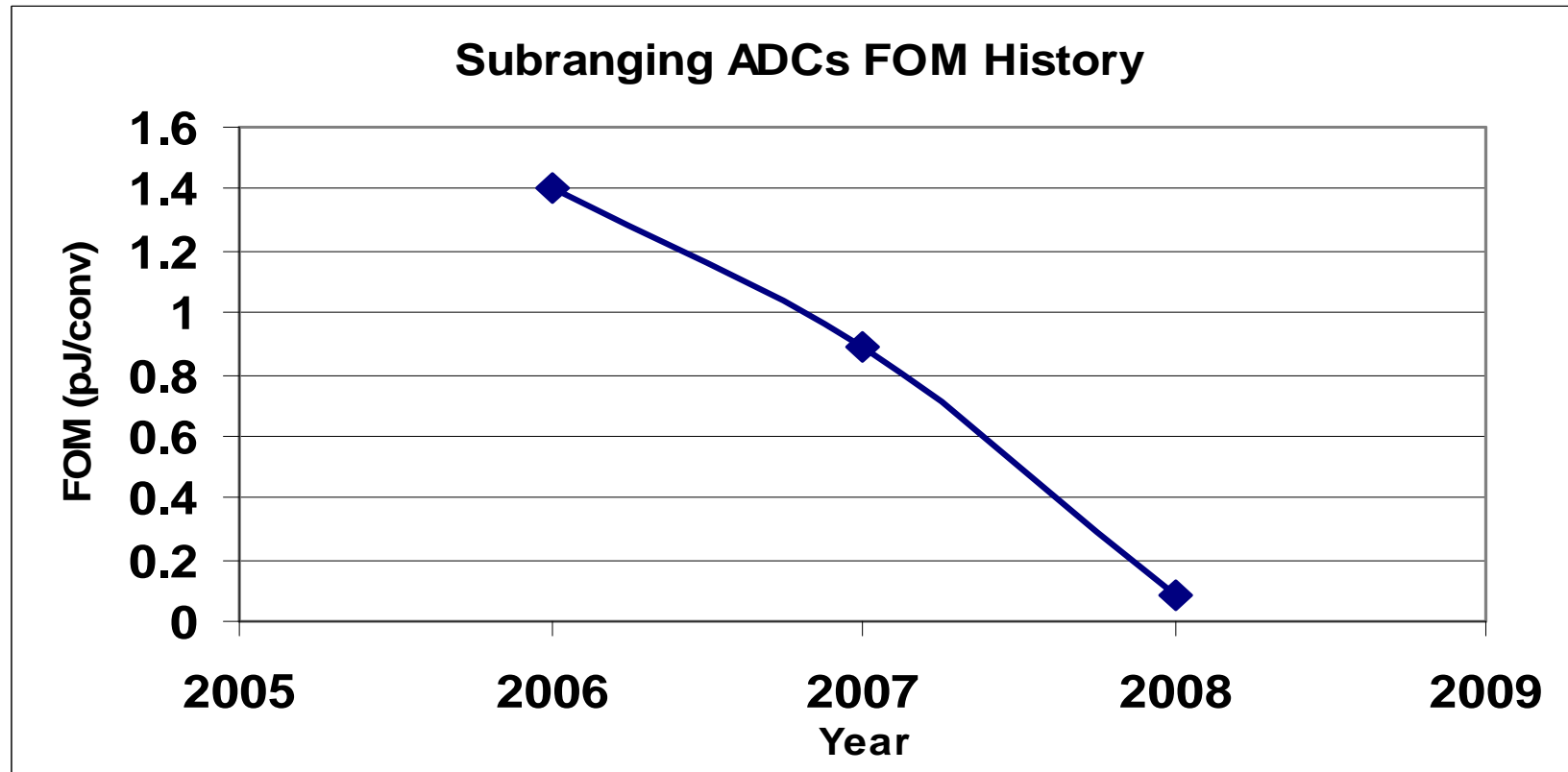
Two-step: subranging ADC

- + $2(2^{N/2}-1)$ comparators
Coarse bank selects which part of reference ladder to connect to fine bank
- Speed limited by settling of fine references
parasitic capacitance from $> 2^N$ switches + large kickback



Source: BRCM

Lost time- Need twice the time and S/H.
Resistor get glitches now impedance is important
New many switches (2 to the $N - M$ Coarse connection)



2006 → 6b & 1Gs/s (90nm CMOS)

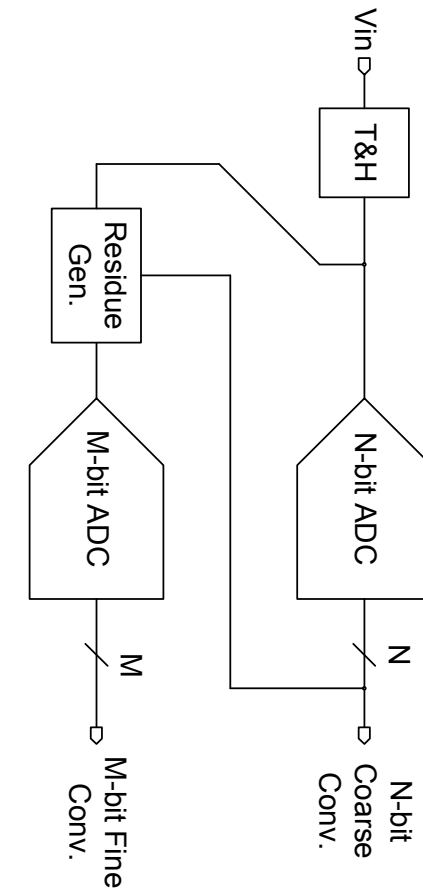
2007 → 10b & 160Ms/s (90nm CMOS)

2008 → 5b & 1.75Gs/s (90nm CMOS)

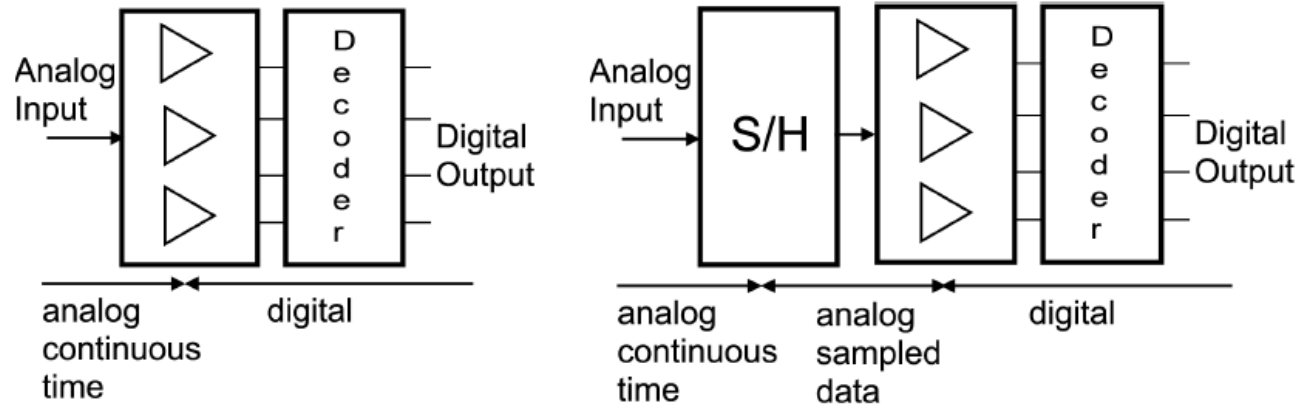
Summary: : Sub-ranging ADCs



- Power efficient
 - Two low resolution ADCs operating in a pipeline manner
- Reduced speed
 - Throughput can be still very high
- T&H is inevitable
 - The most critical component in the architecture
 - Loading is relaxed
- Residue generation
 - Needs $M+N$ bit accuracy
- Interleaving is possible
- State of FOM is around 0.5pJ/conv



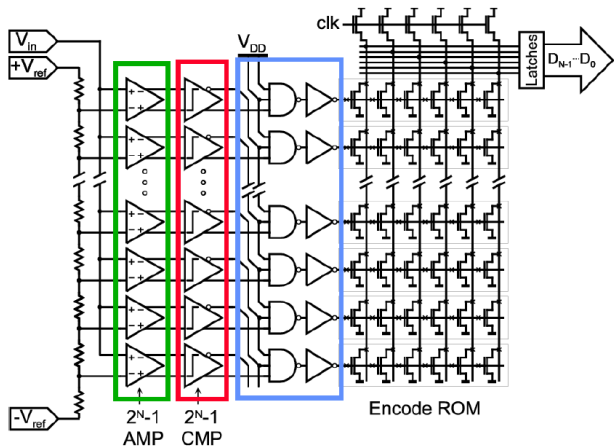
SH Versus clocked flash (“mandatory” in Sub-Ranging



Source: KU Leuven

SH will draw 20-40% more power

Flash architecture with digital corrections 1GHz/6 bits



- Avantages :
- Remove sample and hold – make clocking harder
 - Use comparators as sample and hold
 - Use pre gain comparator – Option
 - Error correction logic
 - ROM Grey encoder
 - Now task is on the clock to be accurate to all comparators



Capacitive Charge FLASH



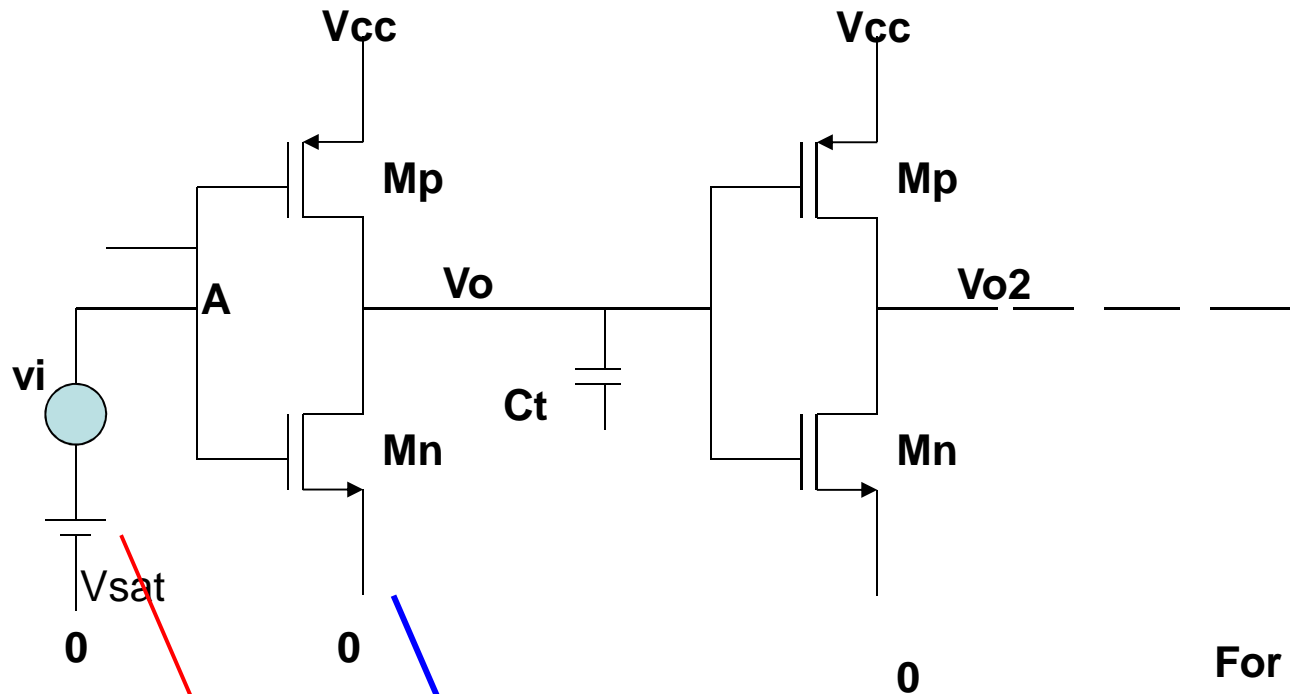
Save power- simplified the complex comparator design
Can we use an inverter as simple gain stage
Use capacitors to transfer $(V_{in} - V_{ref}) \times \text{gain}$.

Why ?

Inverter is a digital cell no special process needs
It draw 0 DC current (power)
very fast and simple, power is lower..
(Offset cancellation is build in) !

With 2 capacitors..we can build a simpler comparator

Operation- Inverter chain- as gain stage



For each stage

$$A_v(\text{dc}) = (g_{Mn} + g_{Mp}) \times r_{op} // r_{on}$$

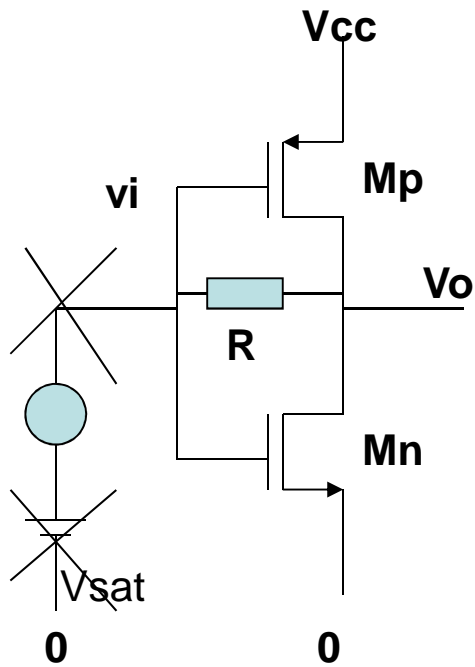
$$\text{Pole} = 1 / 2\pi C_t (r_{op} // r_{on})$$

Amplification is done but

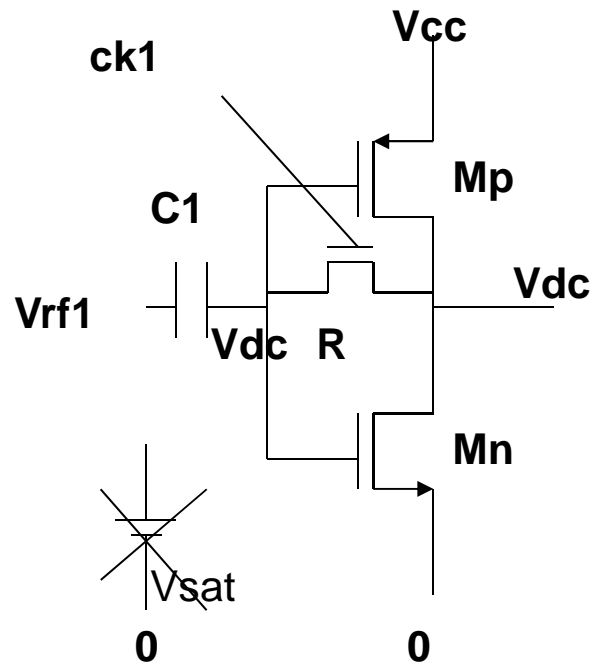
Next how to fix the DC, mid point ? (in saturation)

Next: Can we create differences with one input- at A

Fix the DC point and insert the first input level across a capacitor

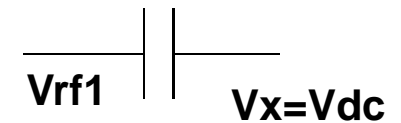


Step 1



Step 2
Ck1=H

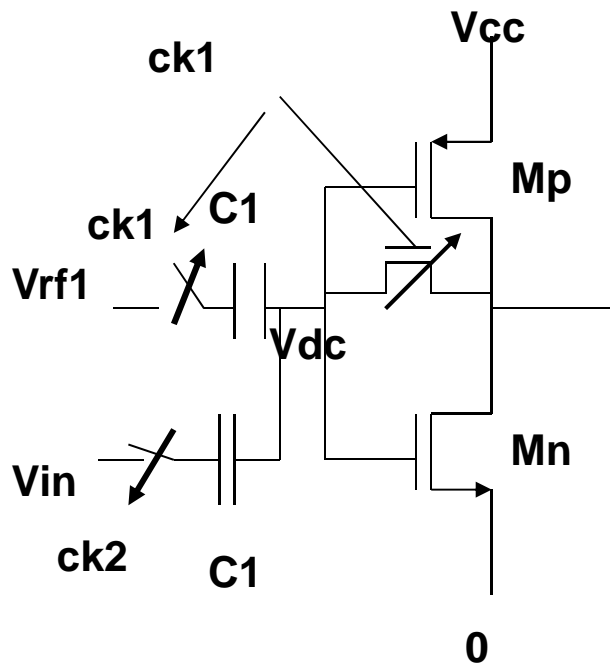
Model at ck1=1



$$Q1 = C(V_{rf1} - V_x)$$

$v_0 = v_i$ the inv. is for sure in Saturation and in low gain/impedance

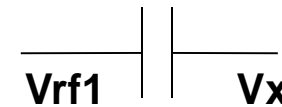
Insert the second level - Subtraction and gain



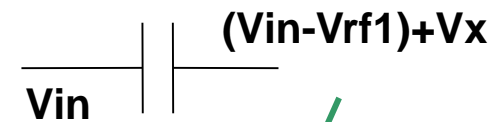
$V_0 = (V_{rf1} - V_{in})A_o(f)$
And No offset.

$$Q_1 = C(V_{rf1} - V_x)$$

Model at $ck_1=1$



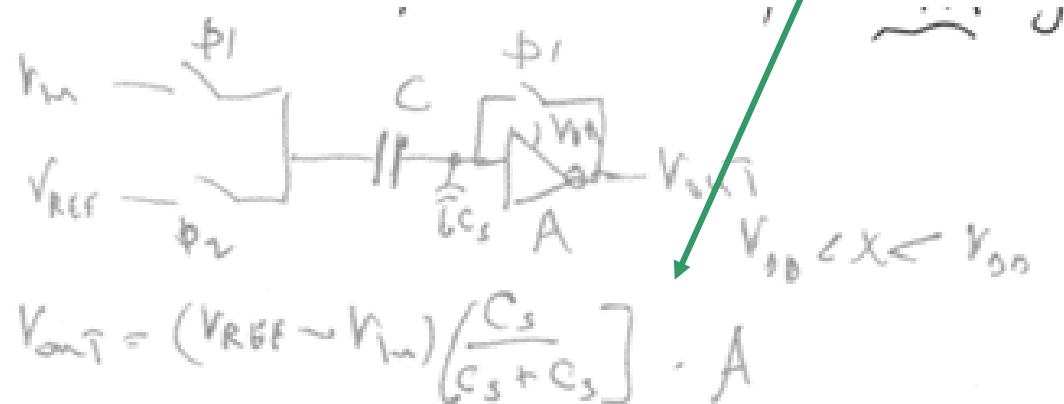
Model at $ck_1=0$



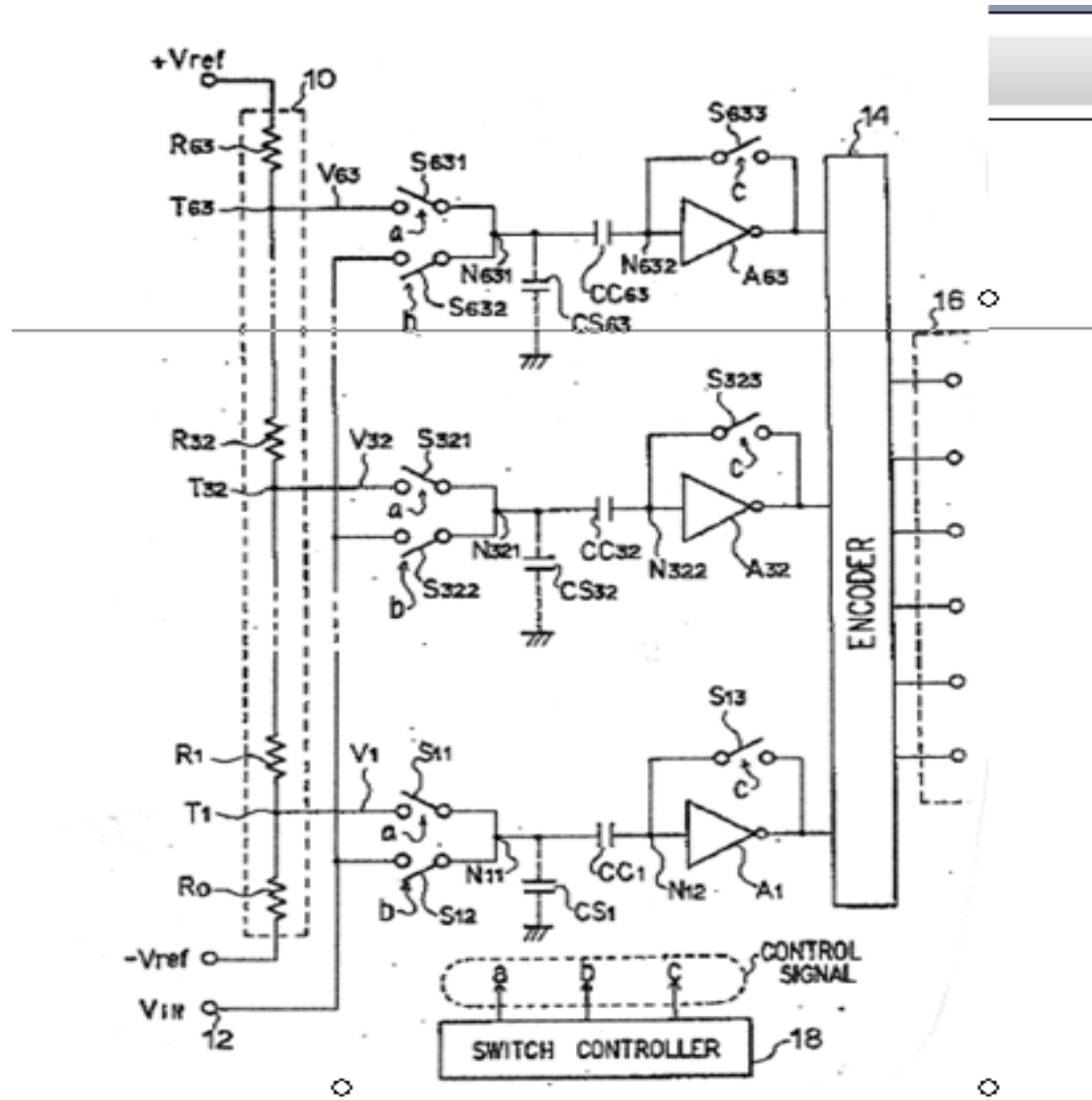
Step 3
Ck1=0
Ck2=H



derivative



Example: Create the ladder codes.



Source: Fairchild Data sheet

Lect 07

Speed example in class..



Speed Estimation:

6 bit ADC, no S/H

At L min 130 nm ($C_{ox} \sim 13 \text{ff/}\mu\text{m}^2$) can get to 1-2 GHz – Flash “only”

Example:

Input Delay = 150ps ($5.5/2\pi R C_{in} + R_{ladder} C_{gs}/2$ to drive 63 comp/calibrate)

+ 250ps comparator + 100ps logic (25ps/gate) = 500ps max

Possibly latch after comp and save some of the 100ps . (50ps)

Sample at 2.0GHz max through put (Input frequency)

twice the min delay $\sim 1 \text{ GHz}$



**Differential /improved implementation
In FLASH architecture**

Differential Design

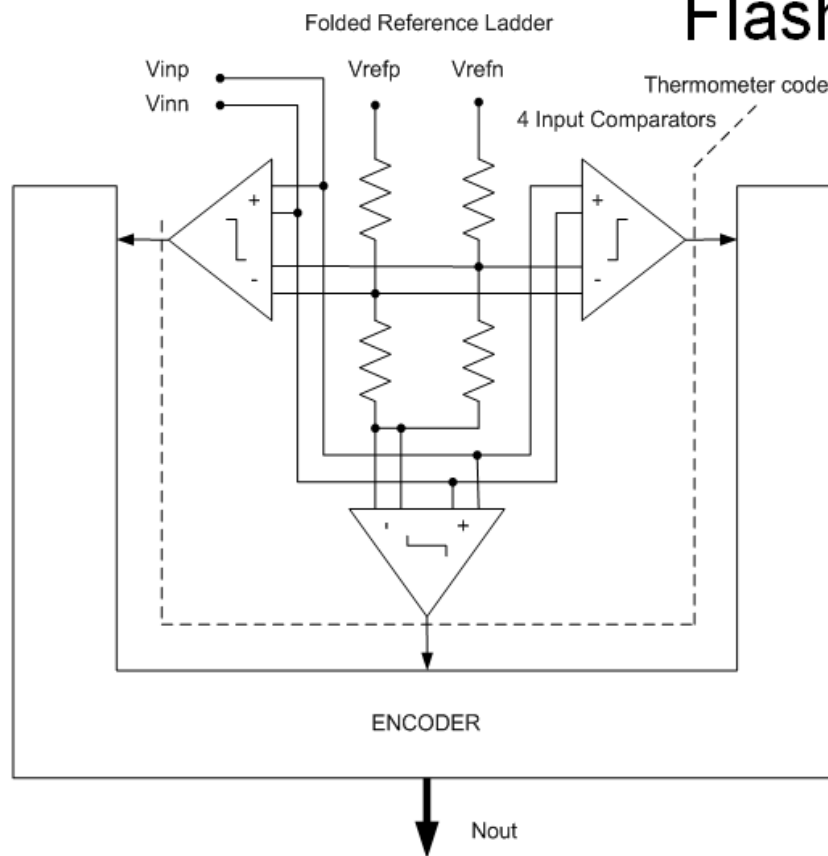
DIFFERENTIAL



INL GOES TO 0 In the middle
Signal is doubled routing is harder

Simple to make differential comparator

Flash ADC Basics (2)



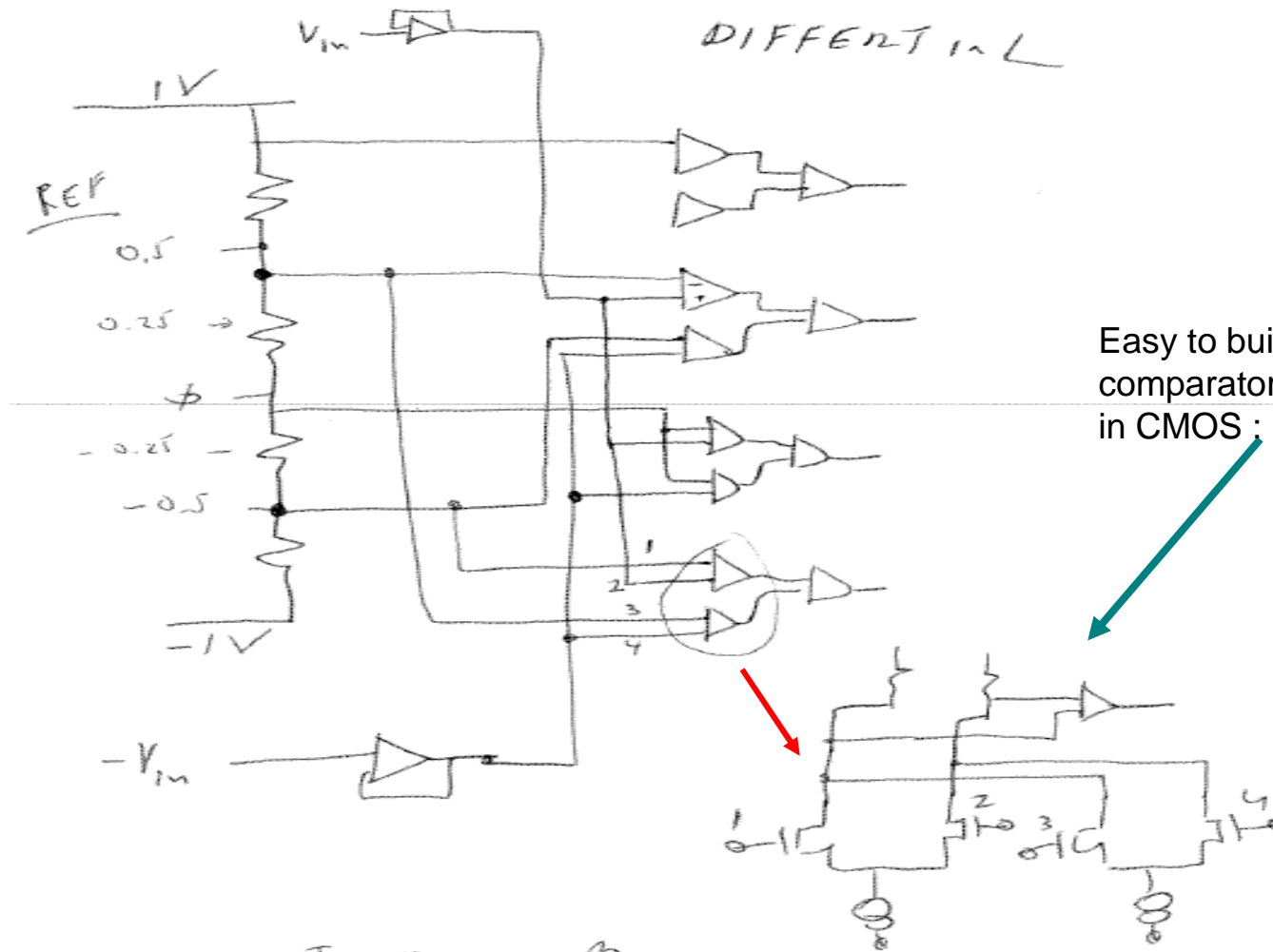
Fully differential implementation:

- wider dynamic range
- better noise immunity
- better linearity

Other reasons :

Symmetry is preserved HD2, HD4 get reduced/cancelled

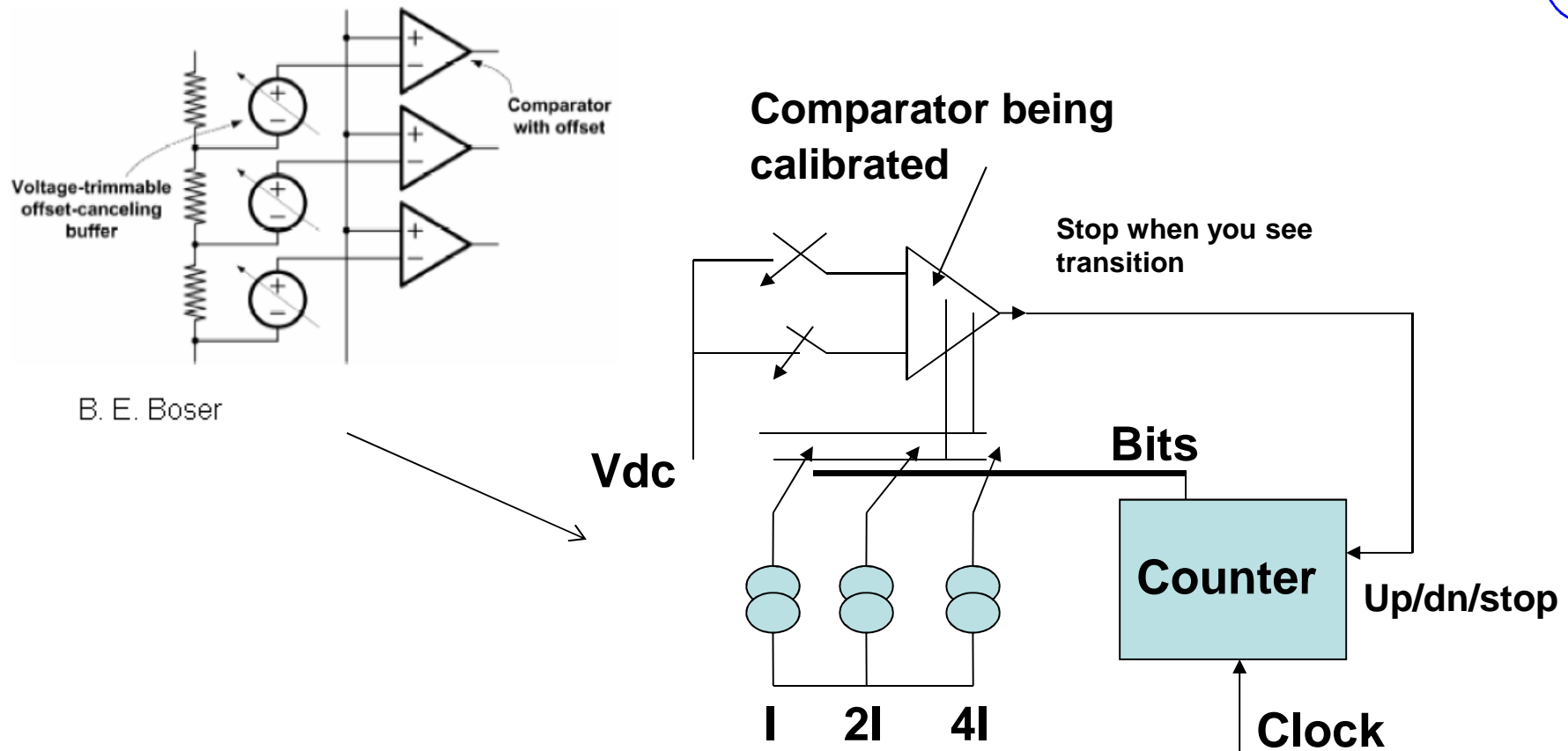
DIFFERENTIAL-details



Easy to build 4 input comparator and to sum currents in CMOS :

- * FLOAT FROM 0
- * USE CM MID POINT
- * 2x SIGNAL, ROUTING ! ok for 3-4 bits

Offset Cancellation/reduction



Select ~7I for maximum offset possible

Alternative offset cancellation



Easy to do in start up.

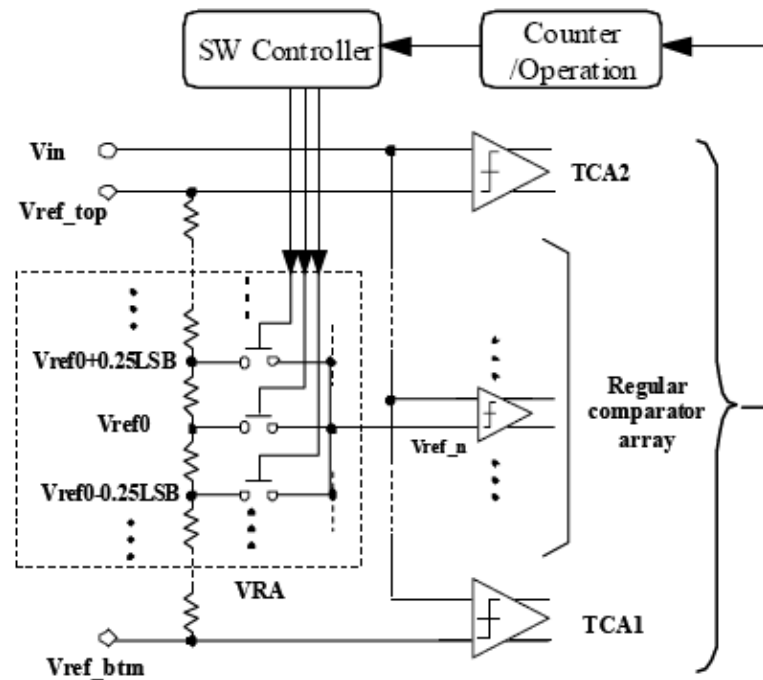


Figure 2: Architecture of offset cancel circuit.

We can go “wild” with good ideas:

Find offset connect comparator to different point on the ladder

Add small DAC to each comparator find trip point (Feed back)- last foil.

Remember the offset in digital code and offset the digital information

Offset Calibrating Comparator Array for 1.2-V, 6-bit, 4-Gsample/s Flash ADCs using 0.13-um generic CMOS technology

Hiroyuki Okada, Yasuyuki Hashimoto,
Kohji Sakata, Toshiro Tsukada, Koichiro Ishibashi



End lecture 07 part a.

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